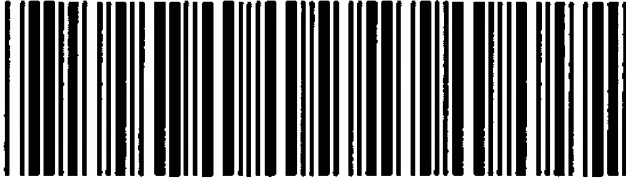


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/661,862	NGUYEN ET AL.	
	Examiner	Art Unit	
	Hai L. Nguyen	2816	

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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Shepardize Search	3/5/2005	HLN